

A Method for Non-Referential Defect Characterization

Disclosure Number

200000883

Technology Summary

A computer vision-based system for performing non-referential defect detection in digital images is described. The system is intended for use in applications where a reference image is either unavailable or is of insufficient quality to be used as a reliable basis for comparison.

Inventor

GLEASON, SHAUN S

Engineering Science & Technology Div

Licensing Contact

SPEIGHT II, MELVIN D

UT-Battelle, LLC

Oak Ridge National Laboratory

Room 143, 4500N, MS: 6196

1 Bethel Valley Road

Oak Ridge, TN 37831

Office Phone: (865) 241-6564

E-mail: DSPEIGHT@ORNL.GOV

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